

Low Phase Noise XO (9.5-65MHz Output)

FEATURES

- 19MHz to 65MHz crystal input.
- Output range: 9.5MHz – 65MHz
- Selectable OE Logic (enable high or enable low).
- Available outputs: PECL, LVDS, or CMOS (High Drive (30mA) or Standard Drive (10mA) output).
- Supports 2.5V or 3.3V Power Supply.
- Available in die form.

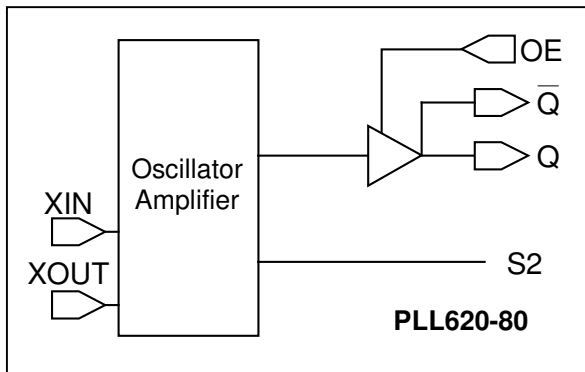
DESCRIPTION

The PLL620-80 is a XO IC specifically designed to work with fundamental or 3rd OT crystals between 19MHz and 65MHz. The selectable divide by two feature extends the operation range from 9.5MHz to 65MHz. It requires very low current into the crystal resulting in better overall stability. The OE logic feature allows selection of enable high or enable low. Furthermore, it provides selectable CMOS, PECL or LVDS outputs.

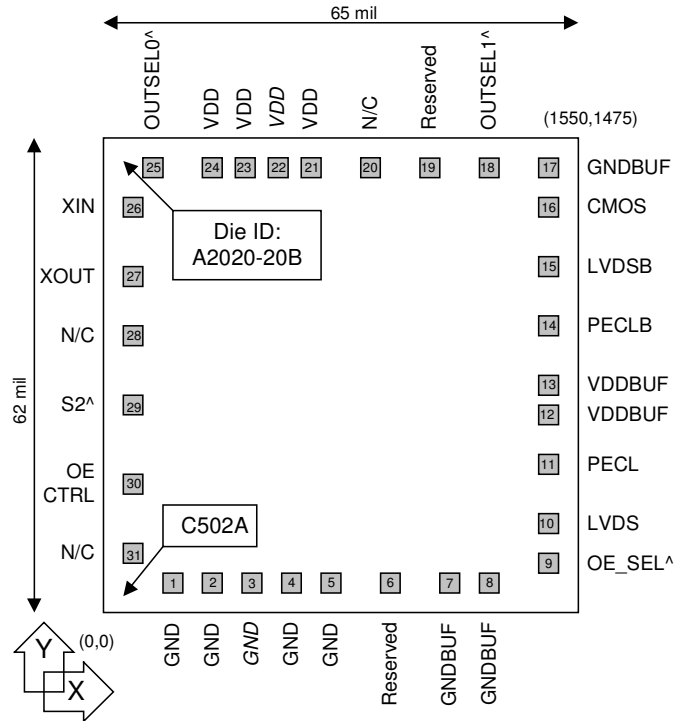
DIE SPECIFICATIONS

| Name | Value |
|----------------|-----------------------|
| Size | 62 x 65 mil |
| Reverse side | GND |
| Pad dimensions | 80 micron x 80 micron |
| Thickness | 10 mil |

BLOCK DIAGRAM



DIE CONFIGURATION



OUTPUT SELECTION AND ENABLE

| OUT_SEL1* (Pad 18) | OUT_SELO* (Pad 25) | Selected Output* |
|-----------------------|-----------------------|------------------|
| 0 | 0 | High Drive CMOS |
| 0 | 1 | Standard CMOS |
| 1 | 0 | LVDS |
| 1 | 1 | PECL (default) |

| OE_SELECT (Pad 9) | OE_CTRL (Pad 30) | State |
|----------------------|---------------------|----------------|
| 0 | 0 | Tri-state |
| | 1 (Default) | Output enabled |
| 1 (Default) | 0 (Default) | Output enabled |
| | 1 | Tri-state |

Pads #9, #18 & #25: Bond to GND to set to "0",
No connection results to "default" setting through internal pull-up.

OE_CTRL: Logical states defined by PECL levels if OE_SELECT is "1"
Logical states defined by CMOS levels if OE_SELECT is "0"

OUTPUT FREQUENCY SELECTOR

| S2 | Output |
|-------------|---------|
| 0 | Input/2 |
| 1(Default)* | Input |

*Internally set to 'Default' through 60KΩ pull-up resistor

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ELECTRICAL SPECIFICATIONS

1. Absolute Maximum Ratings

| PARAMETERS | SYMBOL | MIN. | MAX. | UNITS |
|-----------------------------------|----------|------|--------------|-------|
| Supply Voltage | V_{DD} | | 4.6 | V |
| Input Voltage, dc | V_I | -0.5 | $V_{DD}+0.5$ | V |
| Output Voltage, dc | V_O | -0.5 | $V_{DD}+0.5$ | V |
| Storage Temperature | T_S | -65 | 150 | °C |
| Ambient Operating Temperature* | T_A | -40 | 85 | °C |
| Junction Temperature | T_J | | 125 | °C |
| Lead Temperature (soldering, 10s) | | | 260 | °C |
| ESD Protection, Human Body Model | | | 2 | kV |

Exposure of the device under conditions beyond the limits specified by Maximum Ratings for extended periods may cause permanent damage to the device and affect product reliability. These conditions represent a stress rating only, and functional operations of the device at these or any other conditions above the operational limits noted in this specification is not implied.

* Note: Operating Temperature is guaranteed by design for all parts (COMMERCIAL and INDUSTRIAL), but tested for COMMERCIAL grade only.

2. Crystal Specifications

| PARAMETERS | SYMBOL | CONDITIONS | MIN. | TYP. | MAX. | UNITS |
|-----------------------------|--------------|-------------|------|------|------|----------|
| Crystal Resonator Frequency | F_{XIN} | Fundamental | 19 | | 65 | MHz |
| Crystal Loading Rating | C_L (xtal) | Die | | 8* | | pF |
| Interelectrode Capacitance | C_0 | | | | 5 | pF |
| Recommended ESR | R_E | AT cut | | | 30 | Ω |

Note: Parameters denoted with an asterisk (*) represent nominal characterization data and are not production tested to any specific limits.

3. General Electrical Specifications

| PARAMETERS | SYMBOL | CONDITIONS | MIN. | TYP. | MAX. | UNITS |
|---------------------------------|----------|--------------------------|------|----------|-----------|-------|
| Supply Current (Loaded Outputs) | I_{DD} | PECL/LVDS/CMOS | | | 100/80/40 | mA |
| Operating Voltage | V_{DD} | | 2.97 | | 3.63 | V |
| Output Clock Duty Cycle | | @ 50% V_{DD} (CMOS) | 45 | 50 | 55 | % |
| | | @ 1.25V (LVDS) | 45 | 50 | 55 | |
| | | @ $V_{DD} - 1.3V$ (PECL) | 45 | 50 | 55 | |
| Short Circuit Current | | | | ± 50 | | mA |

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4. Jitter Specifications

| PARAMETERS | CONDITIONS | MIN. | TYP. | MAX. | UNITS |
|--|--|------|------|------|-------|
| Period jitter RMS at 27MHz | With capacitive decoupling between VDD and GND. Over 10,000 cycles | | 2.3 | | ps |
| Period jitter peak-to-peak at 27MHz | | | 18.5 | 20 | |
| Accumulated jitter RMS at 27MHz | With capacitive decoupling between VDD and GND. Over 1,000,000 cycles. | | 2.3 | | ps |
| Accumulated jitter peak-to-peak at 27MHz | | | 24 | 25 | |
| Random Jitter | "RJ" measured on Wavecrest SIA 3000 | | 2.3 | | ps |

Measured on Wavecrest SIA 3000

5. Phase Noise Specifications

| PARAMETERS | FREQUENCY | @10Hz | @100Hz | @1kHz | @10kHz | @100kHz | UNITS |
|---------------------------------|-----------|-------|--------|-------|--------|---------|--------|
| Phase Noise relative to carrier | 27MHz | -75 | -100 | -125 | -140 | -145 | dBc/Hz |

Note: Phase Noise measured on Agilent E5500

6. CMOS Output Electrical Specifications

| PARAMETERS | SYMBOL | CONDITIONS | MIN. | TYP. | MAX. | UNITS |
|--|-----------------|--|------|------|------|-------|
| Output drive current (High Drive) | I _{OH} | V _{OH} = V _{DD} -0.4V, V _{DD} =3.3V | 30 | | | mA |
| | I _{OL} | V _{OL} = 0.4V, V _{DD} = 3.3V | 30 | | | mA |
| Output drive current (Standard Drive) | I _{OH} | V _{OH} = V _{DD} -0.4V, V _{DD} =3.3V | 10 | | | mA |
| | I _{OL} | V _{OL} = 0.4V, V _{DD} = 3.3V | 10 | | | mA |
| Output Clock Rise/Fall Time (Standard Drive) | | 0.3V ~ 3.0V with 15 pF load | | 2.4 | | ns |
| Output Clock Rise/Fall Time (High Drive) | | 0.3V ~ 3.0V with 15 pF load | | 1.2 | | |

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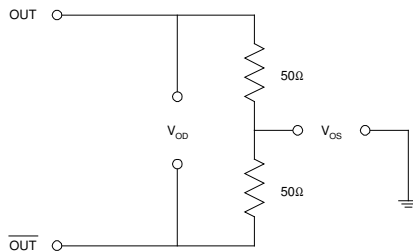
7. LVDS Electrical Characteristics

| PARAMETERS | SYMBOL | CONDITIONS | MIN. | TYP. | MAX. | UNITS |
|------------------------------|-----------------|--|-------|---------|----------|---------|
| Output Differential Voltage | V_{OD} | $R_L = 100 \Omega$ (see figure) | 247 | 355 | 454 | mV |
| V_{DD} Magnitude Change | ΔV_{OD} | | -50 | | 50 | mV |
| Output High Voltage | V_{OH} | | | 1.4 | 1.6 | V |
| Output Low Voltage | V_{OL} | | 0.9 | 1.1 | | V |
| Offset Voltage | V_{OS} | | 1.125 | 1.2 | 1.375 | V |
| Offset Magnitude Change | ΔV_{OS} | | 0 | 3 | 25 | mV |
| Power-off Leakage | I_{OXD} | $V_{out} = V_{DD}$ or GND $V_{DD} = 0V$ | | ± 1 | ± 10 | μA |
| Output Short Circuit Current | I_{OSD} | | | -5.7 | -8 | mA |

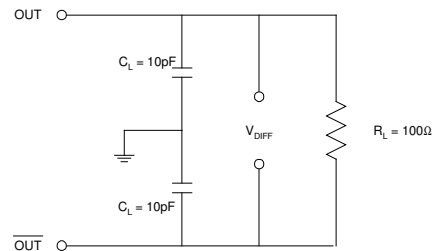
8. LVDS Switching Characteristics

| PARAMETERS | SYMBOL | CONDITIONS | MIN. | TYP. | MAX. | UNITS |
|------------------------------|--------|---|------|------|------|-------|
| Differential Clock Rise Time | t_r | $R_L = 100 \Omega$ $C_L = 10 \text{ pF}$ (see figure) | 0.2 | 0.7 | 1.0 | ns |
| Differential Clock Fall Time | t_f | | 0.2 | 0.7 | 1.0 | ns |

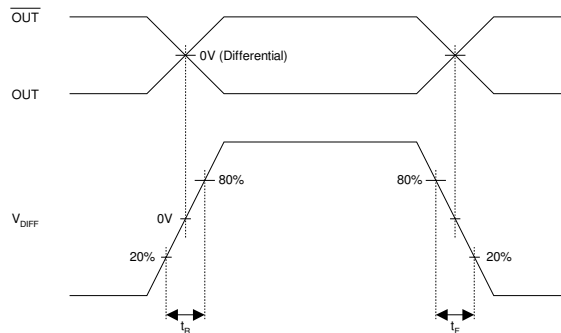
LVDS Levels Test Circuit



LVDS Switching Test Circuit



LVDS Transition Time Waveform



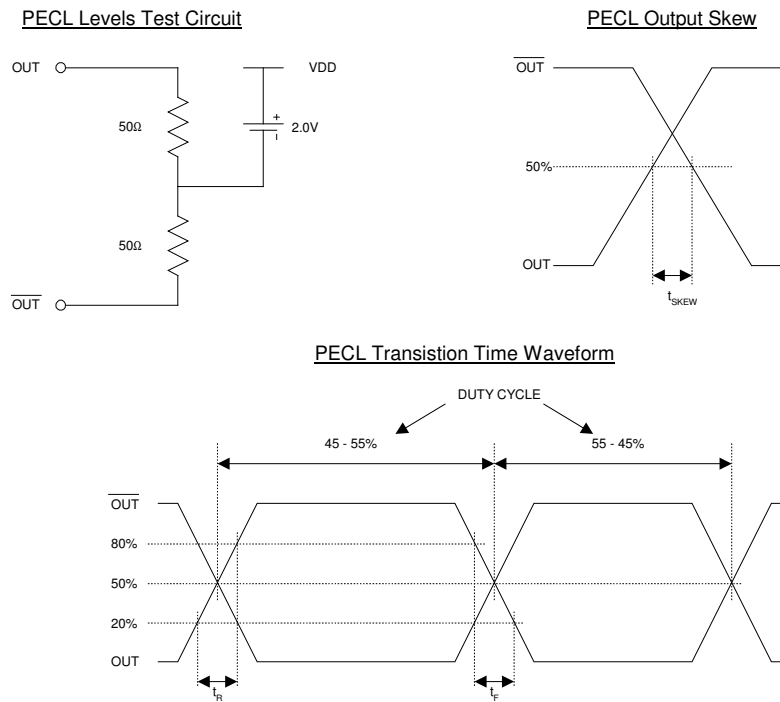
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9. PECL Electrical Characteristics

| PARAMETERS | SYMBOL | CONDITIONS | MIN. | MAX. | UNITS |
|---------------------|----------|--|------------------|------------------|-------|
| Output High Voltage | V_{OH} | $R_L = 50 \Omega$ to $(V_{DD} - 2V)$ (see figure) | $V_{DD} - 1.025$ | | V |
| Output Low Voltage | V_{OL} | | | $V_{DD} - 1.620$ | V |

10. PECL Switching Characteristics

| PARAMETERS | SYMBOL | CONDITIONS | MIN. | TYP. | MAX. | UNITS |
|-----------------|--------|----------------|------|------|------|-------|
| Clock Rise Time | t_r | @20/80% - PECL | | 0.6 | 1.5 | ns |
| Clock Fall Time | t_f | @80/20% - PECL | | 0.5 | 1.5 | ns |



Low Phase Noise XO (9.5-65MHz Output)
PAD DESCRIPTIONS

| Pad # | Name | X (μm) | Y (μm) | Description |
|-------|----------------------|--------|--------|--|
| 1 | GND | 248 | 109 | Ground. |
| 2 | GND | 361 | 109 | Ground. |
| 3 | <i>Optional GND</i> | 473 | 109 | Optional Ground. |
| 4 | GND | 587 | 109 | Ground. |
| 5 | GND | 702 | 109 | Ground. |
| 6 | <i>Reserved</i> | 874 | 109 | Reserved for future use. |
| 7 | GNDBUF | 1042 | 109 | Ground, buffer circuitry. |
| 8 | GNDBUF | 1171 | 109 | Ground, buffer circuitry. |
| 9 | OE_SEL | 1400 | 125 | This is the selector input to choose the OE control logic. See the OE SELECTION AND ENABLE table on page 1. Internal pull up. |
| 10 | LVDS | 1400 | 259 | LVDS output. |
| 11 | PECL | 1400 | 476 | PECL output. |
| 12 | VDDBUF | 1400 | 616 | Power supply, buffer circuitry. |
| 13 | VDDBUF | 1400 | 716 | Power supply, buffer circuitry. |
| 14 | PECLB | 1400 | 871 | Complementary PECL output. |
| 15 | LVDSB | 1400 | 1089 | Complementary LVDS output. |
| 16 | CMOS | 1400 | 1227 | CMOS output. |
| 17 | GNDBUF | 1389 | 1365 | Ground, buffer circuitry. |
| 18 | OUTSEL1 | 1232 | 1365 | Selector input to choose the selected output type (PECL, LVDS, CMOS). See the OUTPUT SELECTION AND ENABLE table on page 1. Internal pull up. |
| 19 | <i>Reserved</i> | 1042 | 1365 | Reserved for future use. |
| 20 | <i>Not connected</i> | 854 | 1365 | Not Connected. |
| 21 | VDD | 659 | 1365 | Power supply. |
| 22 | <i>Optional VDD</i> | 559 | 1365 | Optional Power supply. |
| 23 | VDD | 459 | 1365 | Power supply. |
| 24 | VDD | 358 | 1365 | Power supply. |
| 25 | OUTSEL0 | 194 | 1365 | Selector input to choose the selected output type (PECL, LVDS, CMOS). See the OUTPUT SELECTION AND ENABLE table on page 1. Internal pull up. |
| 26 | XIN | 109 | 1223 | Crystal input. See Crystal Specifications on page 3. |
| 27 | XOUT | 109 | 1017 | Crystal output. See Crystal Specifications on page 3. |
| 28 | <i>Not connected</i> | 109 | 858 | Not Connected. |
| 29 | S2 | 109 | 646 | Output Divide by Two selector pin, as presented on the OUTPUT FREQUENCY SELECTOR Table on page 1. Internal pull up. |
| 30 | OE_CTRL | 109 | 397 | Used to enable/disable the output(s). See Output Selection and Enable table on page 1. |
| 31 | <i>Not connected</i> | 109 | 181 | Not connected. |

Note: for optimal Phase Noise performance, it is recommended to bond all optional VDD and GND pads.

Low Phase Noise XO (9.5-65MHz Output)

ORDERING INFORMATION

For part ordering, please contact our Sales Department:

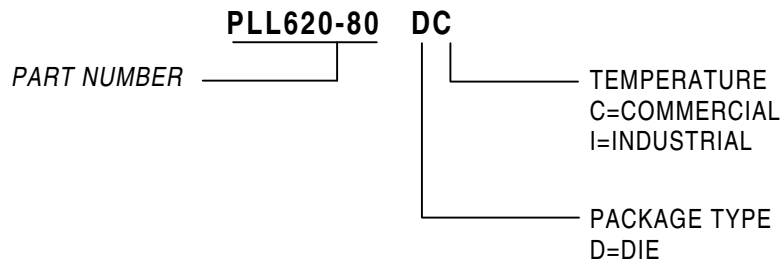
47745 Fremont Blvd., Fremont, CA 94538, USA

Tel: (510) 492-0990 Fax: (510) 492-0991

PART NUMBER

The order number for this device is a combination of the following:

Device number, Package type and Operating temperature range



| <u>Order Number</u> | <u>Marking</u> | <u>Package Option</u> |
|---------------------|----------------|-----------------------|
| PLL620-80DC | P620-80DC | Die – Waffle Pack |

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